# RENESAS

# R1LV0816ABG -5SI, 7SI 8Mb Advanced LPSRAM (512k word x 16bit)

REJ03C0393-0100 Rev.1.00 2009.12.08

#### Description

The R1LV0816ABG is a family of low voltage 8-Mbit static RAMs organized as 524,288-words by 16-bit, fabricated by Renesas's high-performance 0.15um CMOS and TFT technologies.

The R1LV0816ABG is suitable for memory applications where a simple interfacing, battery operating and battery backup are the important design objectives.

The R1LV0816ABG is packaged in a 48balls fine pitch ball grid array [f-BGA / 7.5 mm×8.5mm with the ball-pitch of 0.75mm and 6x8 array]. It gives the best solution for a compaction of mounting area as well as flexibility of wiring pattern of printed circuit boards.

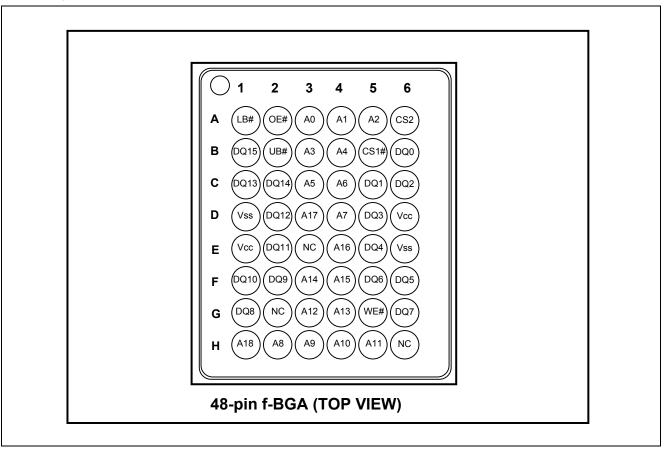
#### Features

- Single 2.4-3.6V power supply
- Small stand-by current: 1.2µA (Vcc=3.0V, typ.)
- No clocks, No refresh
- All inputs and outputs are TTL compatible
- Easy memory expansion by CS1#, CS2, LB# and UB#
- Common Data I/O
- Three-state outputs: OR-tie capability
- OE# prevents data contention in the I/O bus
- Operation temperature: -40 ~ +85°C

#### Ordering information

Туре No.	Power supply	Access time	Temperature Range	Package
R1LV0816ABG-5SI	2.7V to 3.6V	55 ns		49 hall fDCA with 0.75mm hall aitab
RILV0010ADG-001	2.4V to 2.7V	70 ns	-40 ~ +85°C	48-ball fBGA with 0.75mm ball pitch
R1LV0816ABG-7SI	2.4V to 3.6V	70 ns		PTBG0048HB-A(48FHH)

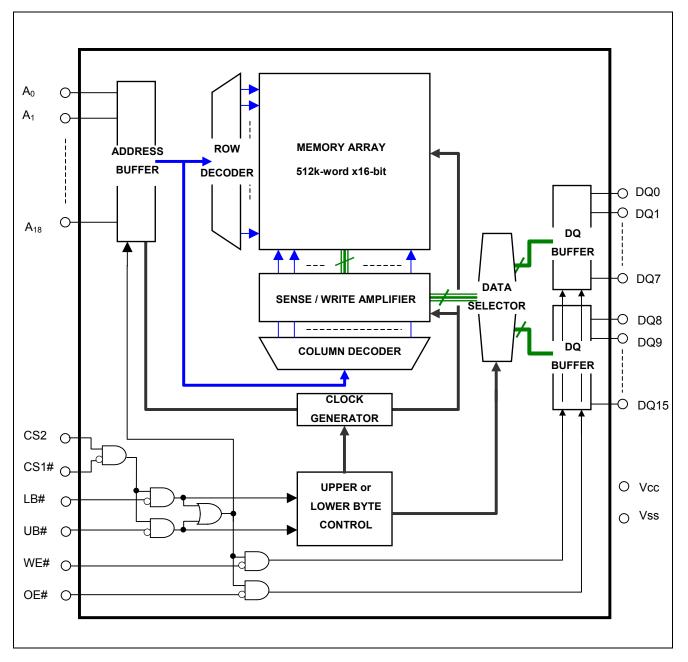
#### Pin Arrangement



# Pin Description

Pin name	Function
Vcc	Power supply
Vss	Ground
A0 to A18	Address input
DQ0 to DQ15	Data input/output
CS1#	Chip select 1
CS2	Chip select 2
WE#	Write enable
OE#	Output enable
LB#	Lower byte enable
UB#	Upper byte enable
NC	Non connection

### Block Diagram



## **Operation Table**

CS1#	CS2	LB#	UB#	WE#	OE#	DQ0~7	DQ8~15	Operation
Н	Х	Х	Х	Х	Х	High-Z	High-Z	Stand-by
Х	L	Х	Х	Х	Х	High-Z	High-Z	Stand-by
Х	Х	H	Н	Х	Х	High-Z	High-Z	Stand-by
L	Н	L	Н	L	Х	Din	High-Z	Write in lower byte
L	Н	L	Н	H	L	Dout	High-Z	Read in lower byte
L	Н	L	Н	H	Н	High-Z	High-Z	Output disable
L	Н	Н	L	L	Х	High-Z	Din	Write in upper byte
L	Н	H	L	H	L	High-Z	Dout	Read in upper byte
L	Н	H	L	H	Н	High-Z	High-Z	Output disable
L	Н	L	L	L	Х	Din	Din	Word write
L	Н	L	L	H	L	Dout	Dout	Word read
L	Н	L	L	Н	Н	High-Z	High-Z	Output disable

Note 1. H:  $V_{IH} \quad L{:}V_{IL} \quad X{:} \; V_{IH} \; or \; V_{IL}$ 

### Absolute Maximum Ratings

Parameter	Symbol	Value	unit
Power supply voltage relative to Vss	Vcc	-0.5 to +4.6	V
Terminal voltage on any pin relative to Vss	VT	-0.5 <sup>*1</sup> to Vcc+0.3 <sup>*2</sup>	V
Power dissipation	PT	0.7	W
Operation temperature	Topr	-40 to +85	°C
Storage temperature range	Tstg	-65 to 150	°C
Storage temperature range under bias	Tbias	-40 to +85	°C

Note 1. -3.0V in case of AC (Pulse width ≤30ns)

2. Maximum voltage is +4.6V

### **Recommend Operating Conditions**

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions	Note
Supply voltage	Vcc	2.4	3.0	3.6	V	-	
	Vss	0	0	0	V	-	
Input high voltage	V	2.0	-	Vcc+0.2	V	Vcc=2.4V to 2.7V	
	V <sub>IH</sub>	2.2	-	Vcc+0.2	V	Vcc=2.7V to 3.6V	
Input low voltage	V	-0.2	-	0.4	V	Vcc=2.4V to 2.7V	1
	V <sub>IL</sub>	-0.2	-	0.6	V	Vcc=2.7V to 3.6V	1
Ambient temperature range	Та	-40	-	+85	°C	-	

Note 1. -3.0V in case of AC (Pulse width ≤30ns)

### **DC** Characteristics

Parameter	Symbol	Min.	Тур.	Max.	Unit		Test conditions	
Input leakage current	I <sub>U</sub>	-	-	1	μA	Vin = Vss to Vcc		
Output leakage current						CS1# =V	IH or CS2 =VIL or	
	I <sub>LO</sub>	-	-	1	μA	OE# =VIH	i or WE# =V <sub>IL</sub> or	
						LB# = UE	8# =V <sub>IH</sub> , VI/O =Vss to Vcc	
Average operating current	I <sub>CC1</sub>		20 <sup>*1</sup>	35	mA	Min. cycle	e, duty =100%, II/O = 0mA	
-	ICC1	_	20		ША	CS1# =V	$_{IL}$ , CS2 =V $_{IH}$ , Others = V $_{IH}$ /V $_{IL}$	
						-	s, duty =100%, II/O = 0mA	
	I <sub>CC2</sub>	-	2 <sup>*1</sup>	5	mA		$.2V, CS2 \ge V_{CC}-0.2V,$	
							-0.2V, V <sub>IL</sub> ≤ 0.2V	
Standby current	I <sub>SB</sub>	-	0.1 <sup>*1</sup>	0.3	mA	CS2 =V <sub>IL</sub>		
Standby current		-	1.2 <sup>*1</sup>	4	μA	~+25°C	Vin ≥ 0V (1) 0V ≤ CS2 ≤ 0.2V or	
		-	3 <sup>*2</sup>	6	μA	~+40°C	(2) CS1# $\ge$ V <sub>CC</sub> -0.2V, CS2 $\ge$ V <sub>CC</sub> -0.2V or	
	I <sub>SB1</sub>	-	-	15	μA	~+70°C	(3) LB# = UB# ≥ $V_{CC}$ -0.2V, CS1# ≤ 0.2V, CS2 ≥ $V_{CC}$ -0.2V	
		-	-	20	μA	~+85°C		
Output high voltage	V <sub>OH</sub>	2.4	-	-	V	I <sub>OH</sub> = -1mA Vcc≥2.7V		
	V <sub>OH2</sub>	2.0	-	-	V	I <sub>OH</sub> = -0.1	mA	
Output low voltage	V <sub>OL</sub>	-	-	0.4	V	I <sub>OL</sub> = 2mA Vcc≥2.7V		
	V <sub>OL2</sub>	-	-	0.4	V	I <sub>OL</sub> = 0.1n	nA	

Note 1.Typical parameter indicates the value for the center of distribution at 3.0V(Ta=+25°C), and not 100% tested. 2.Typical parameter indicates the value for the center of distribution at 3.0V(Ta=+40°C), and not 100% tested.

#### Capacitance

(Ta =25°C, f =1MHz)

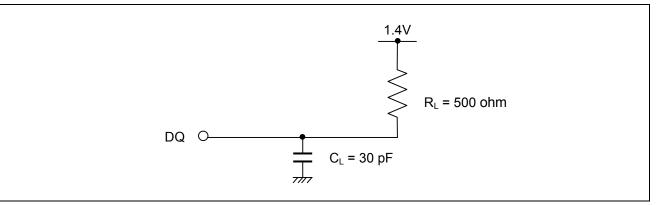
						( )	,
Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions	Note
Input capacitance	C in	-	-	10	pF	Vin =0V	1
Input / output capacitance	C <sub>I/O</sub>	-	-	10	pF	V <sub>I/O</sub> =0V	1

Note 1.Typical parameter is sampled and not 100% tested.

#### **AC Characteristics**

Test Conditions (Vcc =  $2.4V \sim 3.6V$ , Ta =  $-40 \sim +85^{\circ}C$ )

- Input pulse levels: VIL = 0.4V, VIH = 2.4V (Vcc = 2.7V ~ 3.6 V)
   VIL = 0.4V, VIH = 2.2V (Vcc = 2.4V ~ 2.7 V)
- Input rise and fall times: 5ns
- Input and output timing reference level: 1.4V
- Output load: See figures (Including scope and jig)



# Read cycle

Parameter	Symbol	R1LV0816 (No	ABG-5SI te 0)	R1LV081	6ABG-7SI	Unit	Note
		Min.	Max.	Min.	Max.		
Read cycle time	t <sub>RC</sub>	55	-	70	-	ns	
Address access time	t <sub>AA</sub>	-	55	-	70	ns	
Chip select access time	t <sub>ACS1</sub>	-	55	-	70	ns	
Chip select access time	t <sub>ACS2</sub>	-	55	-	70	ns	
Output enable to output valid	t <sub>OE</sub>	-	30	-	35	ns	
Output hold from address change	t <sub>он</sub>	10	-	10	-	ns	
LB#, UB# access time	t <sub>BA</sub>	-	55	-	70	ns	
Chip coloct to output in low 7	t <sub>CLZ1</sub>	10	-	10	-	ns	2,3
Chip select to output in low-Z	t <sub>CLZ2</sub>	10	-	10	-	ns	2,3
LB#, UB# enable to low-Z	t <sub>BLZ</sub>	5	-	5	-	ns	2,3
Output enable to output in low-Z	t <sub>oLZ</sub>	5	-	5	-	ns	2,3
Chip dependent to output in high 7	t <sub>CHZ1</sub>	0	20	0	25	ns	1,2,3
Chip deselect to output in high-Z	t <sub>CHZ2</sub>	0	20	0	25	ns	1,2,3
LB#, UB# disable to high-Z	t <sub>BHZ</sub>	0	20	0	25	ns	1,2,3
Output disable to output in high-Z	t <sub>OHZ</sub>	0	20	0	25	ns	1,2,3

#### Write Cycle

Parameter	Symbol		6ABG-5SI e 0)	R1LV081	6ABG-7SI	Unit	Note
		Min.	Max.	Min.	Max.		
Write cycle time	t <sub>wc</sub>	55	-	70	-	ns	
Address valid to end of write	t <sub>AW</sub>	50	-	65	-	ns	
Chip select to end of write	t <sub>CW</sub>	50	-	65	-	ns	5
Write pulse width	t <sub>WP</sub>	40	-	55	-	ns	4
LB#, UB# valid to end of write	t <sub>BW</sub>	50	-	65	-	ns	
Address setup time	t <sub>AS</sub>	0	-	0	-	ns	6
Write recovery time	t <sub>WR</sub>	0	-	0	-	ns	7
Data to write time overlap	t <sub>DW</sub>	25	-	35	-	ns	
Data hold from write time	t <sub>DH</sub>	0	-	0	-	ns	
Output enable from end of write	t <sub>ow</sub>	5	-	5	-	ns	2
Output disable to output in high-Z	t <sub>онz</sub>	0	20	0	25	ns	1,2
Write to output in high-Z	t <sub>WHZ</sub>	0	20	0	25	ns	1,2

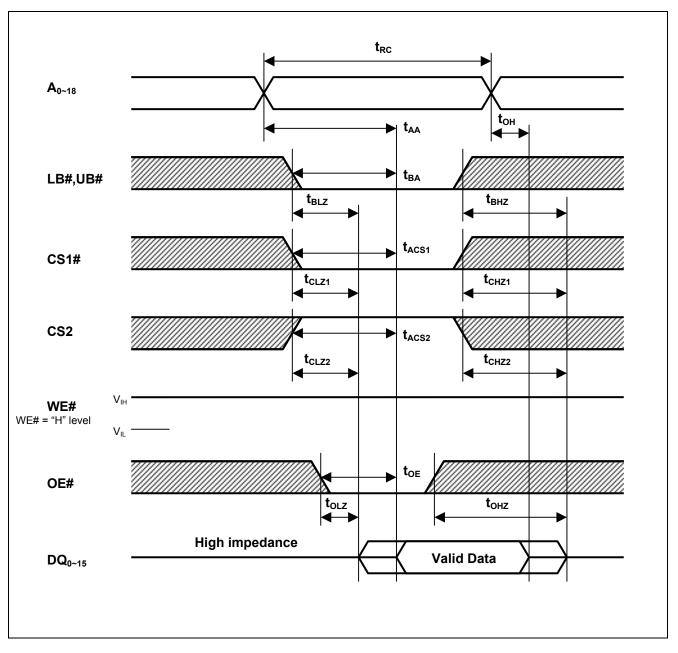
Note 0. If Vcc is 2.4-2.7V, parameters of R1LV0816ABG-7SI (70ns) are applied.

- 1. t<sub>CHZ</sub>, t<sub>OHZ</sub>, t<sub>WHZ</sub> and t<sub>BHZ</sub> are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.
- 2. Typical parameter is sampled and not 100% tested.
- 3. At any given temperature and voltage condition,  $t_{HZ}$  max is less than  $t_{LZ}$  min both for given device and from device to device.
- 4. A write occurs during the overlap of a low CS1#, a high CS2, a low WE# and a low LB# or low UB#. A write begins at the latest transitions among CS1# going low, CS2 going high, WE# going low and LB# going low or UB# going low.
- A write ends at the earliest transitions among CS1# going high, CS2 going low, WE# going high and LB# going high or UB# going high. t<sub>WP</sub> is measured from the beginning of write to the end of write.
- 5. t<sub>CW</sub> is measured from the later of CS1# going low or CS2 going high to the end of write.
- 6. t<sub>AS</sub> is measured the address valid to the beginning of write.

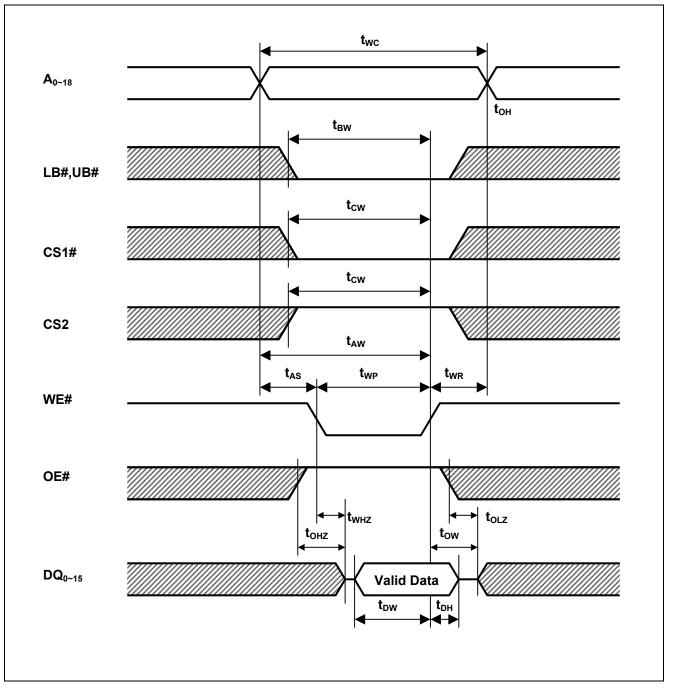
7. twR is measured from the earliest of CS1# or WE# going high or CS2 going low to the end of write cycle

### **Timing Waveforms**

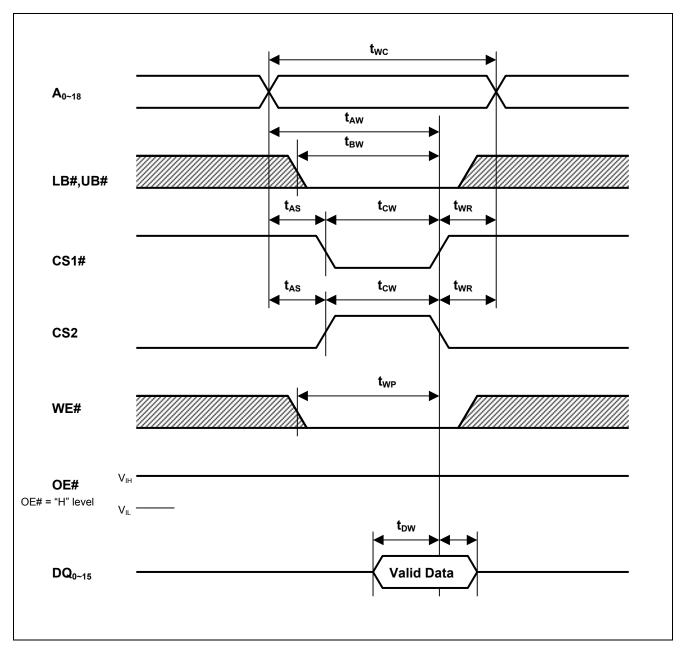




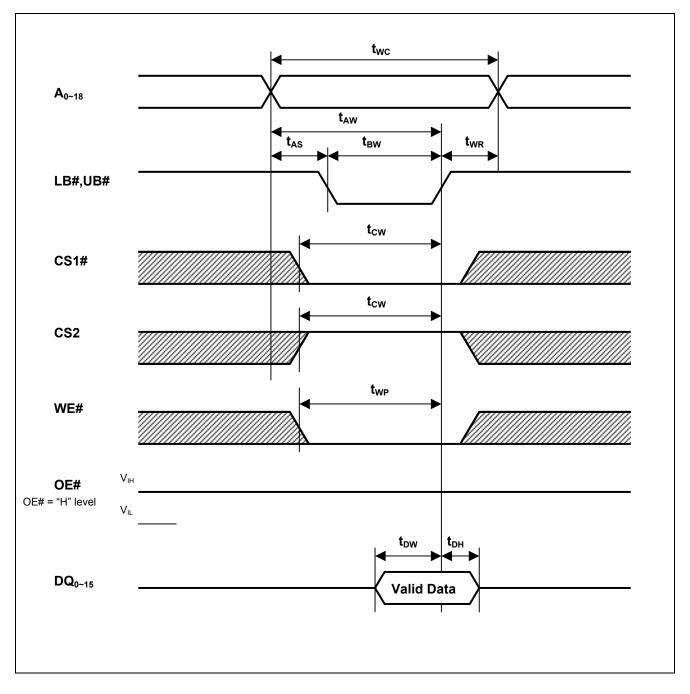
### Write Cycle (1) (WE# CLOCK)



Write Cycle (2) (CS1#, CS2 CLOCK)



Write Cycle (3) (LB#, UB# CLOCK)



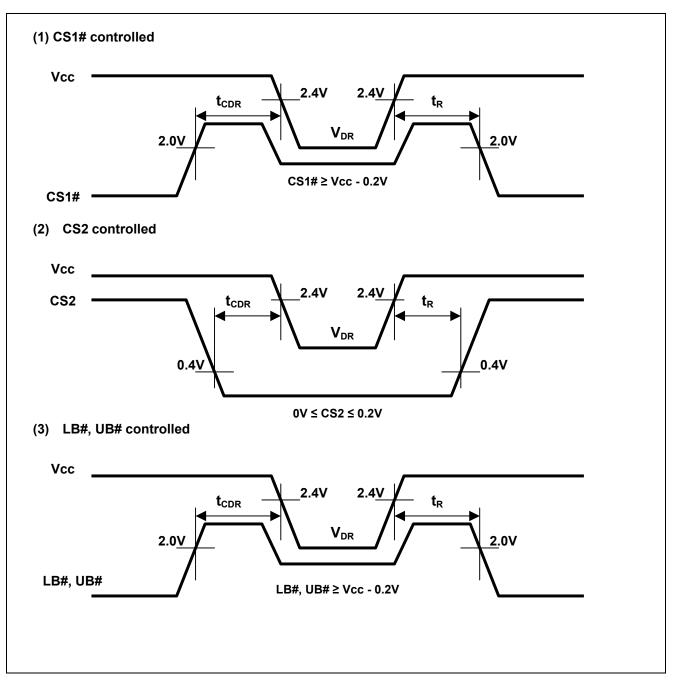
### Data Retention Characteristics

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions <sup>*3</sup>		
$V_{\text{CC}}$ for data retention	V <sub>DR</sub>	1.5	-	3.6	V	(2) CS1# CS2 ≥ (3) LB# = CS1# ≤	CS2 ≤ 0.2V or ≥ $V_{CC}$ -0.2V, $V_{CC}$ -0.2V or $=$ UB# ≥ $V_{CC}$ -0.2V, ≤ 0.2V, $V_{CC}$ -0.2V	
		-	1.2 <sup>*1</sup>	4	μA	~+25°C	Vcc=3.0V, Vin ≥ 0V	
Data ratentian auroant		-	3 <sup>*2</sup>	6	μA	~+40°C	(1) $0V \le CS2 \le 0.2V$ or (2) $CS1\# \ge V_{CC}-0.2V$ ,	
Data retention current	ICCDR	-	-	15	μA	~+70°C	CS2 ≥ V <sub>CC</sub> -0.2V or (3) LB# = UB# ≥ V <sub>CC</sub> -0.2V, CS1# ≤ 0.2V,	
		-	-	20	μA	~+85°C	$CS2 \ge V_{CC}-0.2V$	
Chip select to data retention time	t <sub>CDR</sub>	0	-	-	ns	See retention waveform.		
Operation recovery time	t <sub>R</sub>	5	-	-	ms			

Note 1.Typical parameter indicates the value for the center of distribution at 3.0V(Ta=+25°C), and not 100% tested. 2.Typical parameter indicates the value for the center of distribution at 3.0V(Ta=+40°C), and not 100% tested. 3.CS2 controls address buffer, WE# buffer, CS1# Buffer, OE# buffer, LB#, UB# buffer and Din buffer.

If CS2 controls data retention mode, Vin levels (address, WE#, OE#, LB#, UB#, DQ) can be in the high impedance state. If CS1# controls data retention mode, CS2 must be CS2  $\geq$  V<sub>CC</sub>-0.2V or 0V  $\leq$  CS2  $\leq$  0.2V. The other inputs levels (address, WE#, OE#, CS1#, LB#, UB#, DQ) can be in the high impedance state.

Data Retention Timing Waveforms



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